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### **Understanding Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### **Details**

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	742
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1020-BBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	<a href="https://www.e-xfl.com/pro/item?MUrl=&amp;PartUrl=ep2s180f1020c4">https://www.e-xfl.com/pro/item?MUrl=&amp;PartUrl=ep2s180f1020c4</a>

After compilation, check the information messages for a full list of I/O, DQ, LVDS, and other pins that are not available because of the selected migration path.

Table 1–4 lists the Stratix II device package offerings and shows the total number of non-migratable user I/O pins when migrating from one density device to a larger density device. Additional I/O pins may not be migratable if migrating from the larger device to the smaller density device.



When moving from one density to a larger density, the larger density device may have fewer user I/O pins. The larger device requires more power and ground pins to support the additional logic within the device. Use the Quartus II Pin Planner to determine which user I/O pins are migratable between the two devices.

Vertical Migration Path	484-Pin FineLine BGA	672-Pin FineLine BGA	780-Pin FineLine BGA	1020-Pin FineLine BGA	1508-Pin FineLine BGA
EP2S15 to EP2S30	0 (1)	0			
EP2S15 to EP2S60	8 (1)	0			
EP2S30 to EP2S60	8 (1)	8			
EP2S60 to EP2S90				0	
EP2S60 to EP2S130				0	
EP2S60 to EP2S180				0	
EP2S90 to EP2S130			0 (1)	16	17
EP2S90 to EP2S180				16	0
EP2S130 to EP2S180				0	0

**Note to Table 1–4:**

- (1) Some of the DQ/DQS pins are not migratable. Refer to the Quartus II software information messages for more detailed information.



To determine if your user I/O assignments are correct, run the I/O Assignment Analysis command in the Quartus II software (Processing > Start > Start I/O Assignment Analysis).



Refer to the *I/O Management* chapter in volume 2 of the *Quartus II Handbook* for more information on pin migration.

Each Stratix II device I/O pin is fed by an I/O element (IOE) located at the end of LAB rows and columns around the periphery of the device. I/O pins support numerous single-ended and differential I/O standards. Each IOE contains a bidirectional I/O buffer and six registers for registering input, output, and output-enable signals. When used with dedicated clocks, these registers provide exceptional performance and interface support with external memory devices such as DDR and DDR2 SDRAM, RLDRAM II, and QDR II SRAM devices. High-speed serial interface channels with dynamic phase alignment (DPA) support data transfer at up to 1 Gbps using LVDS or HyperTransport™ technology I/O standards.

Figure 2-1 shows an overview of the Stratix II device.

Figure 2-1. Stratix II Block Diagram

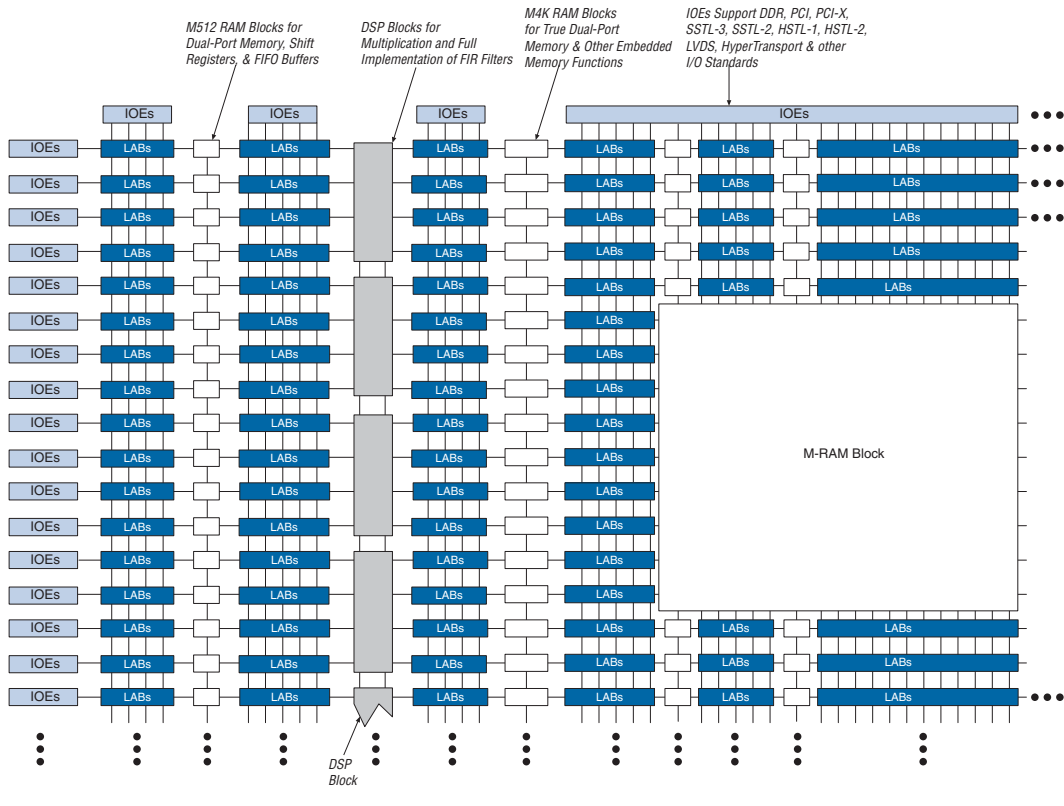
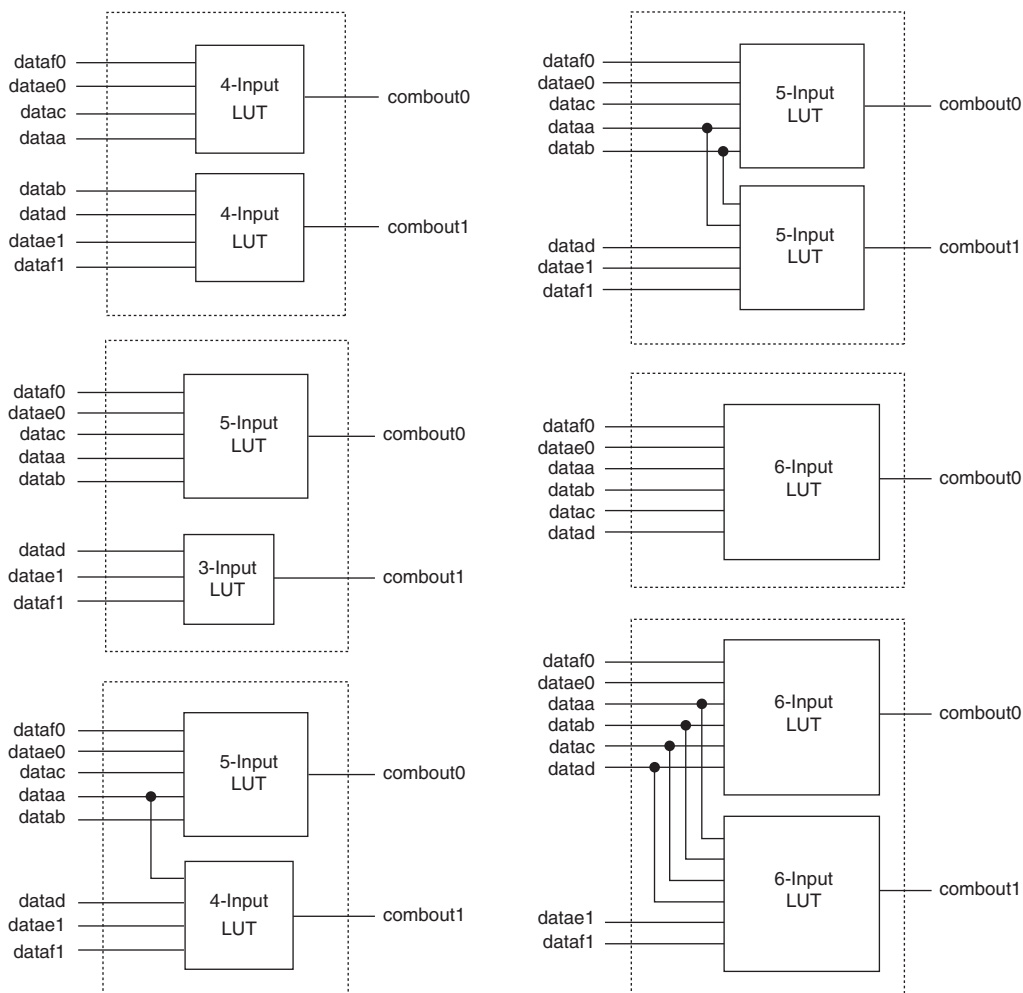


Figure 2-7. ALM in Normal Mode *Note (1)***Note to Figure 2-7:**

- (1) Combinations of functions with fewer inputs than those shown are also supported. For example, combinations of functions with the following number of inputs are supported: 4 and 3, 3 and 3, 3 and 2, 5 and 2, etc.

The normal mode provides complete backward compatibility with four-input LUT architectures. Two independent functions of four inputs or less can be implemented in one Stratix II ALM. In addition, a five-input function and an independent three-input function can be implemented without sharing inputs.



## Clear & Preset Logic Control

LAB-wide signals control the logic for the register's clear and load/preset signals. The ALM directly supports an asynchronous clear and preset function. The register preset is achieved through the asynchronous load of a logic high. The direct asynchronous preset does not require a NOT-gate push-back technique. Stratix II devices support simultaneous asynchronous load/preset, and clear signals. An asynchronous clear signal takes precedence if both signals are asserted simultaneously. Each LAB supports up to two clears and one load/preset signal.

In addition to the clear and load/preset ports, Stratix II devices provide a device-wide reset pin (`DEV_CLRn`) that resets all registers in the device. An option set before compilation in the Quartus II software controls this pin. This device-wide reset overrides all other control signals.

## MultiTrack Interconnect

In the Stratix II architecture, connections between ALMs, TriMatrix memory, DSP blocks, and device I/O pins are provided by the MultiTrack interconnect structure with DirectDrive™ technology. The MultiTrack interconnect consists of continuous, performance-optimized routing lines of different lengths and speeds used for inter- and intra-design block connectivity. The Quartus II Compiler automatically places critical design paths on faster interconnects to improve design performance.

DirectDrive technology is a deterministic routing technology that ensures identical routing resource usage for any function regardless of placement in the device. The MultiTrack interconnect and DirectDrive technology simplify the integration stage of block-based designing by eliminating the re-optimization cycles that typically follow design changes and additions.

The MultiTrack interconnect consists of row and column interconnects that span fixed distances. A routing structure with fixed length resources for all devices allows predictable and repeatable performance when migrating through different device densities. Dedicated row interconnects route signals to and from LABs, DSP blocks, and TriMatrix memory in the same row. These row resources include:

- Direct link interconnects between LABs and adjacent blocks
- R4 interconnects traversing four blocks to the right or left
- R24 row interconnects for high-speed access across the length of the device

**Figure 2–26. M-RAM Row Unit Interface to Interconnect**

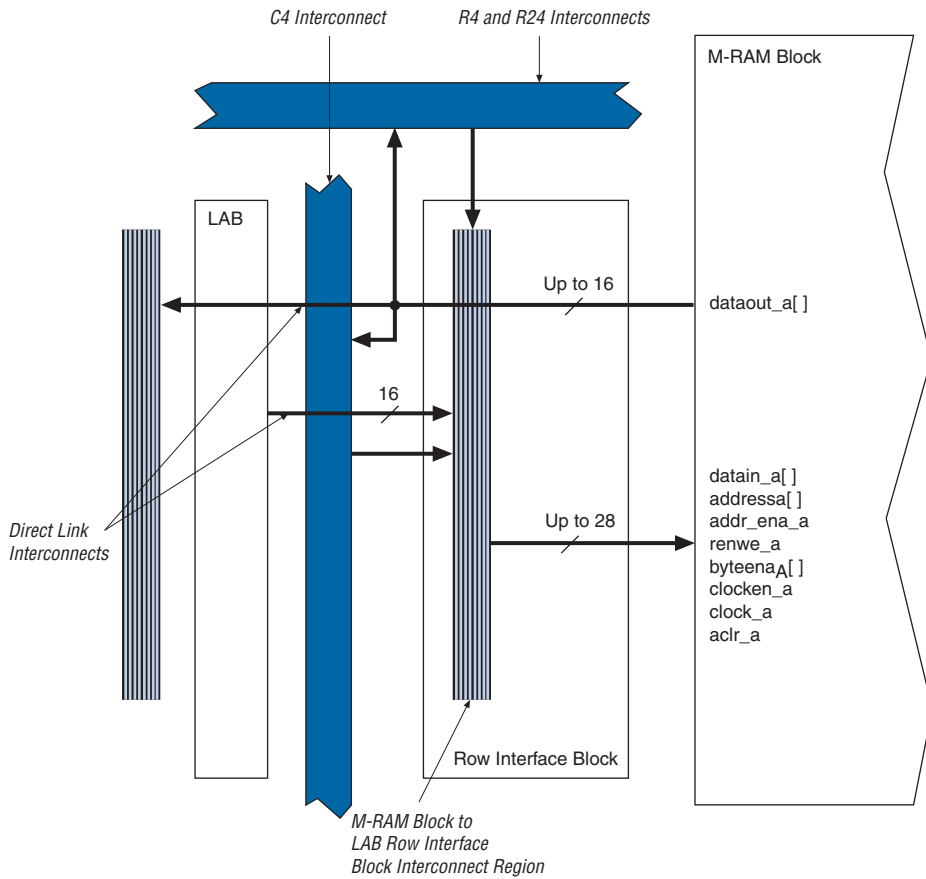


Table 2–4 shows the input and output data signal connections along with the address and control signal input connections to the row unit interfaces (L0 to L5 and R0 to R5).

## Digital Signal Processing Block

The most commonly used DSP functions are FIR filters, complex FIR filters, IIR filters, fast Fourier transform (FFT) functions, direct cosine transform (DCT) functions, and correlators. All of these use the multiplier as the fundamental building block. Additionally, some applications need specialized operations such as multiply-add and multiply-accumulate operations. Stratix II devices provide DSP blocks to meet the arithmetic requirements of these functions.

Each Stratix II device has from two to four columns of DSP blocks to efficiently implement DSP functions faster than ALM-based implementations. Stratix II devices have up to 24 DSP blocks per column (see [Table 2-5](#)). Each DSP block can be configured to support up to:

- Eight  $9 \times 9$ -bit multipliers
- Four  $18 \times 18$ -bit multipliers
- One  $36 \times 36$ -bit multiplier

As indicated, the Stratix II DSP block can support one  $36 \times 36$ -bit multiplier in a single DSP block. This is true for any combination of signed, unsigned, or mixed sign multiplications.

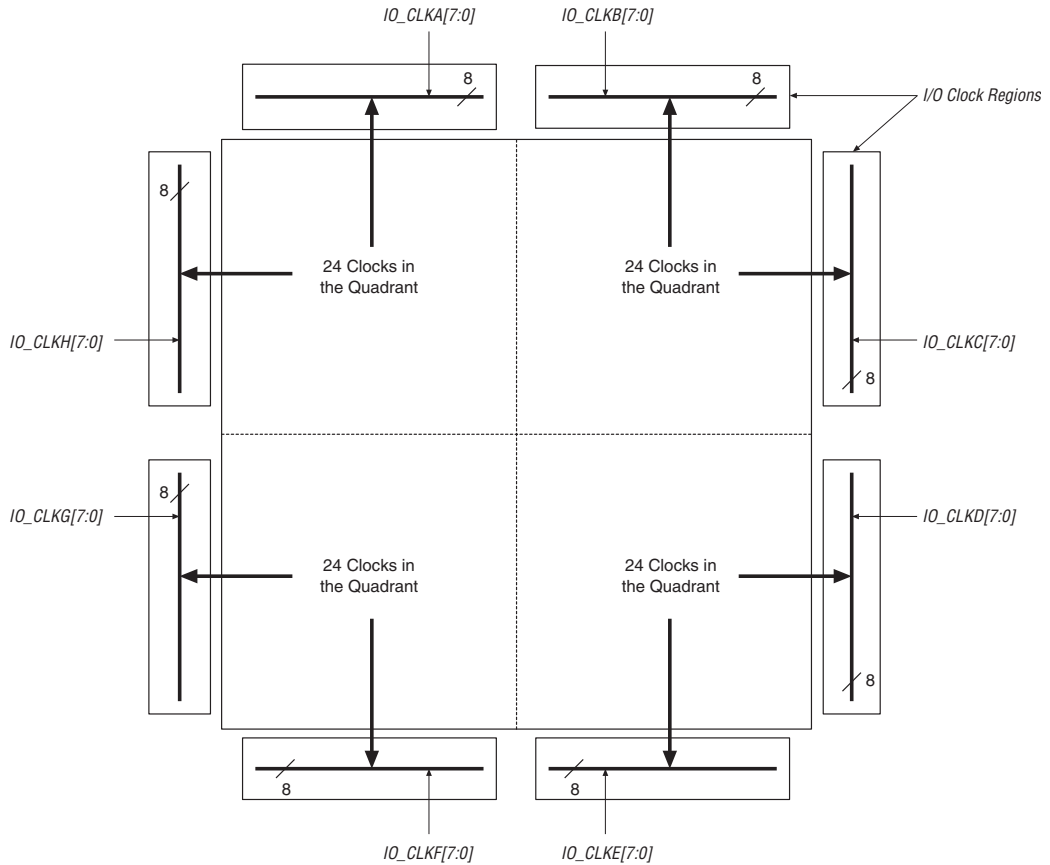


This list only shows functions that can fit into a single DSP block. Multiple DSP blocks can support larger multiplication functions.



IOE clocks have row and column block regions that are clocked by eight I/O clock signals chosen from the 24 quadrant clock resources. Figures 2-35 and 2-36 show the quadrant relationship to the I/O clock regions.

Figure 2-35. EP2S15 & EP2S30 Device I/O Clock Groups



**Table 2–11. Global & Regional Clock Connections from Top Clock Pins & Enhanced PLL Outputs (Part 2 of 2)**

Top Side Global & Regional Clock Network Connectivity	DLLCLK	CLK12	CLK13	CLK14	CLK15	RCLK24	RCLK25	RCLK26	RCLK27	RCLK28	RCLK29	RCLK30	RCLK31
c4	✓					✓		✓		✓		✓	
c5	✓						✓		✓		✓		✓
Enhanced PLL 11 outputs													
c0		✓	✓			✓				✓			
c1		✓	✓				✓				✓		
c2				✓	✓			✓				✓	
c3				✓	✓				✓				✓
c4						✓		✓		✓		✓	
c5							✓		✓		✓		✓

**Table 2–12. Global & Regional Clock Connections from Bottom Clock Pins & Enhanced PLL Outputs (Part 1 of 2)**

Bottom Side Global & Regional Clock Network Connectivity	DLLCLK	CLK4	CLK5	CLK6	CLK7	RCLK8	RCLK9	RCLK10	RCLK11	RCLK12	RCLK13	RCLK14	RCLK15
Clock pins													
CLK4p	✓	✓	✓			✓				✓			
CLK5p	✓	✓	✓				✓				✓		
CLK6p	✓			✓	✓			✓				✓	
CLK7p	✓			✓	✓				✓				✓
CLK4n		✓				✓				✓			
CLK5n			✓				✓				✓		
CLK6n				✓				✓				✓	
CLK7n					✓				✓				✓
Drivers from internal logic													
GCLKDRV0		✓											
GCLKDRV1			✓										
GCLKDRV2				✓									

**Table 2–16. Stratix II Supported I/O Standards (Part 2 of 2)**

I/O Standard	Type	Input Reference Voltage ( $V_{REF}$ ) (V)	Output Supply Voltage ( $V_{CCIO}$ ) (V)	Board Termination Voltage ( $V_{TT}$ ) (V)
SSTL-2 Class I and II	Voltage-referenced	1.25	2.5	1.25

**Notes to Table 2–16:**

- (1) This I/O standard is only available on input and output column clock pins.
- (2) This I/O standard is only available on input clock pins and DQS pins in I/O banks 3, 4, 7, and 8, and output clock pins in I/O banks 9, 10, 11, and 12.
- (3)  $V_{CCIO}$  is 3.3 V when using this I/O standard in input and output column clock pins (in I/O banks 9, 10, 11, and 12). The clock input pins supporting LVDS on banks 3, 4, 7, and 8 use  $V_{CCINT}$  for LVDS input operations and have no dependency on the  $V_{CCIO}$  level of the bank.
- (4) 1.2-V HSTL is only supported in I/O banks 4, 7, and 8.



For more information on I/O standards supported by Stratix II I/O banks, refer to the *Selectable I/O Standards in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook*.

Stratix II devices contain eight I/O banks and four enhanced PLL external clock output banks, as shown in [Figure 2–57](#). The four I/O banks on the right and left of the device contain circuitry to support high-speed differential I/O for LVDS and HyperTransport inputs and outputs. These banks support all Stratix II I/O standards except PCI or PCI-X I/O pins, and SSTL-18 Class II and HSTL outputs. The top and bottom I/O banks support all single-ended I/O standards. Additionally, enhanced PLL external clock output banks allow clock output capabilities such as differential support for SSTL and HSTL.

Each I/O bank has its own  $V_{CCIO}$  pins. A single device can support 1.5-, 1.8-, 2.5-, and 3.3-V interfaces; each bank can support a different  $V_{CCIO}$  level independently. Each bank also has dedicated  $V_{REF}$  pins to support the voltage-referenced standards (such as SSTL-2). The PLL banks utilize the adjacent  $V_{REF}$  group when voltage-referenced standards are implemented. For example, if an SSTL input is implemented in PLL bank 10, the voltage level at  $V_{REFB7}$  is the reference voltage level for the SSTL input.

I/O pins that reside in PLL banks 9 through 12 are powered by the  $VCC\_PLL<5, 6, 11, \text{ or } 12>\_OUT$  pins, respectively. The EP2S60F484, EP2S60F780, EP2S90H484, EP2S90F780, and EP2S130F780 devices do not support PLLs 11 and 12. Therefore, any I/O pins that reside in bank 11 are powered by the  $V_{CCIO3}$  pin, and any I/O pins that reside in bank 12 are powered by the  $V_{CCIO8}$  pin.

Each I/O bank can support multiple standards with the same  $V_{CCIO}$  for input and output pins. Each bank can support one  $V_{REF}$  voltage level. For example, when  $V_{CCIO}$  is 3.3 V, a bank can support LVTTTL, LVCMOS, and 3.3-V PCI for inputs and outputs.

## On-Chip Termination

Stratix II devices provide differential (for the LVDS or HyperTransport technology I/O standard), series, and parallel on-chip termination to reduce reflections and maintain signal integrity. On-chip termination simplifies board design by minimizing the number of external termination resistors required. Termination can be placed inside the package, eliminating small stubs that can still lead to reflections.

Stratix II devices provide four types of termination:

- Differential termination ( $R_D$ )
- Series termination ( $R_S$ ) without calibration
- Series termination ( $R_S$ ) with calibration
- Parallel termination ( $R_T$ ) with calibration

error status information. This dedicated remote system upgrade circuitry avoids system downtime and is the critical component for successful remote system upgrades.

RSC is supported in the following Stratix II configuration schemes: FPP, AS, PS, and PPA. RSC can also be implemented in conjunction with advanced Stratix II features such as real-time decompression of configuration data and design security using AES for secure and efficient field upgrades.



See the *Remote System Upgrades With Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook* for more information about remote configuration in Stratix II devices.

### Configuring Stratix II FPGAs with JRunner

JRunner is a software driver that configures Altera FPGAs, including Stratix II FPGAs, through the ByteBlaster II or ByteBlasterMV cables in JTAG mode. The programming input file supported is in Raw Binary File (**.rbf**) format. JRunner also requires a Chain Description File (**.cdf**) generated by the Quartus II software. JRunner is targeted for embedded JTAG configuration. The source code is developed for the Windows NT operating system (OS), but can be customized to run on other platforms.



For more information on the JRunner software driver, see the *JRunner Software Driver: An Embedded Solution to the JTAG Configuration White Paper* and the source files on the Altera web site (**www.altera.com**).

### Programming Serial Configuration Devices with SRunner

A serial configuration device can be programmed in-system by an external microprocessor using SRunner. SRunner is a software driver developed for embedded serial configuration device programming that can be easily customized to fit in different embedded systems. SRunner is able to read a **.rpd** file (Raw Programming Data) and write to the serial configuration devices. The serial configuration device programming time using SRunner is comparable to the programming time when using the Quartus II software.

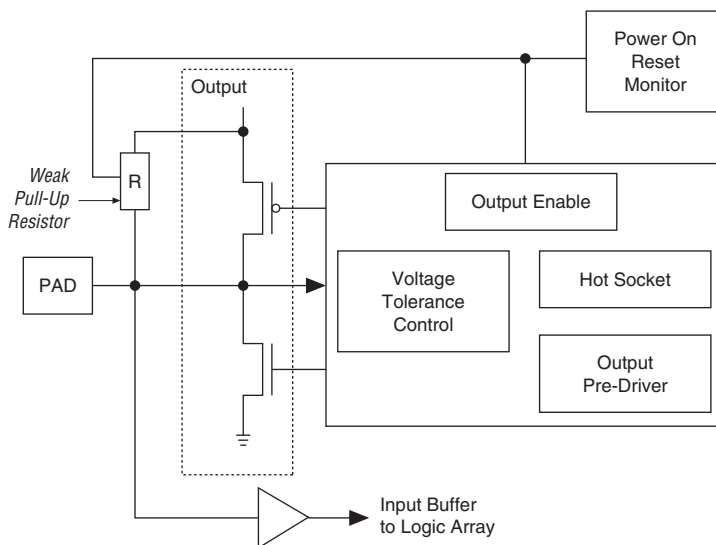


For more information about SRunner, see the *SRunner: An Embedded Solution for EPCS Programming White Paper* and the source code on the Altera web site at **www.altera.com**.



For more information on programming serial configuration devices, see the Serial Configuration Devices (EPCS1 & EPCS4) Data Sheet in the *Configuration Handbook*.

Figure 4-1. Hot Socketing Circuit Block Diagram for Stratix II Devices



The POR circuit monitors  $V_{CCINT}$  voltage level and keeps I/O pins tri-stated until the device is in user mode. The weak pull-up resistor (R) from the I/O pin to  $V_{CCIO}$  is present to keep the I/O pins from floating. The 3.3-V tolerance control circuit permits the I/O pins to be driven by 3.3 V before  $V_{CCIO}$  and/or  $V_{CCINT}$  and/or  $V_{CCPD}$  are powered, and it prevents the I/O pins from driving out when the device is not in user mode. The hot socket circuit prevents I/O pins from internally powering  $V_{CCIO}$ ,  $V_{CCINT}$ , and  $V_{CCPD}$  when driven by external signals before the device is powered.

Figure 4-2 shows a transistor level cross section of the Stratix II device I/O buffers. This design ensures that the output buffers do not drive when  $V_{CCIO}$  is powered before  $V_{CCINT}$  or if the I/O pad voltage is higher than  $V_{CCIO}$ . This also applies for sudden voltage spikes during hot insertion. There is no current path from signal I/O pins to  $V_{CCINT}$  or  $V_{CCIO}$  or  $V_{CCPD}$  during hot insertion. The  $V_{PAD}$  leakage current charges the 3.3-V tolerant circuit capacitance.

**Table 5–14. 3.3-V PCI Specifications (Part 2 of 2)**

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V <sub>IL</sub>	Low-level input voltage		–0.3		0.3 × V <sub>CCIO</sub>	V
V <sub>OH</sub>	High-level output voltage	I <sub>OUT</sub> = –500 μA	0.9 × V <sub>CCIO</sub>			V
V <sub>OL</sub>	Low-level output voltage	I <sub>OUT</sub> = 1,500 μA			0.1 × V <sub>CCIO</sub>	V

**Table 5–15. PCI-X Mode 1 Specifications**

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V <sub>CCIO</sub>	Output supply voltage		3.0		3.6	V
V <sub>IH</sub>	High-level input voltage		0.5 × V <sub>CCIO</sub>		V <sub>CCIO</sub> + 0.5	V
V <sub>IL</sub>	Low-level input voltage		–0.30		0.35 × V <sub>CCIO</sub>	V
V <sub>IPU</sub>	Input pull-up voltage		0.7 × V <sub>CCIO</sub>			V
V <sub>OH</sub>	High-level output voltage	I <sub>OUT</sub> = –500 μA	0.9 × V <sub>CCIO</sub>			V
V <sub>OL</sub>	Low-level output voltage	I <sub>OUT</sub> = 1,500 μA			0.1 × V <sub>CCIO</sub>	V

**Table 5–16. SSTL-18 Class I Specifications**

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V <sub>CCIO</sub>	Output supply voltage		1.71	1.80	1.89	V
V <sub>REF</sub>	Reference voltage		0.855	0.900	0.945	V
V <sub>TT</sub>	Termination voltage		V <sub>REF</sub> – 0.04	V <sub>REF</sub>	V <sub>REF</sub> + 0.04	V
V <sub>IH</sub> (DC)	High-level DC input voltage		V <sub>REF</sub> + 0.125			V
V <sub>IL</sub> (DC)	Low-level DC input voltage				V <sub>REF</sub> – 0.125	V
V <sub>IH</sub> (AC)	High-level AC input voltage		V <sub>REF</sub> + 0.25			V
V <sub>IL</sub> (AC)	Low-level AC input voltage				V <sub>REF</sub> – 0.25	V
V <sub>OH</sub>	High-level output voltage	I <sub>OH</sub> = –6.7 mA (1)	V <sub>TT</sub> + 0.475			V
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 6.7 mA (1)			V <sub>TT</sub> – 0.475	V

Note to Table 5–16:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

**Table 5–25. 1.5-V HSTL Class I & II Differential Specifications**

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
$V_{CCIO}$	I/O supply voltage		1.425	1.500	1.575	V
$V_{DIF}$ (DC)	DC input differential voltage		0.2			V
$V_{CM}$ (DC)	DC common mode input voltage		0.68		0.90	V
$V_{DIF}$ (AC)	AC differential input voltage		0.4			V
$V_{OX}$ (AC)	AC differential cross point voltage		0.68		0.90	V

**Table 5–26. 1.8-V HSTL Class I Specifications**

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
$V_{CCIO}$	Output supply voltage		1.71	1.80	1.89	V
$V_{REF}$	Input reference voltage		0.85	0.90	0.95	V
$V_{TT}$	Termination voltage		0.85	0.90	0.95	V
$V_{IH}$ (DC)	DC high-level input voltage		$V_{REF} + 0.1$			V
$V_{IL}$ (DC)	DC low-level input voltage		-0.3		$V_{REF} - 0.1$	V
$V_{IH}$ (AC)	AC high-level input voltage		$V_{REF} + 0.2$			V
$V_{IL}$ (AC)	AC low-level input voltage				$V_{REF} - 0.2$	V
$V_{OH}$	High-level output voltage	$I_{OH} = 8 \text{ mA}$ (1)	$V_{CCIO} - 0.4$			V
$V_{OL}$	Low-level output voltage	$I_{OH} = -8 \text{ mA}$ (1)			0.4	V

**Note to Table 5–26:**

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.



**Table 5–36. Stratix II Performance Notes (Part 6 of 6)** *Note (1)*

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
Larger designs	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, three multipliers five adders FFT function	7385	60	36	359.58	352.98	312.01	278.00	MHz
	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, four multipliers and two adders FFT function	6601	60	48	371.88	355.74	327.86	277.62	MHz

**Notes for Table 5–36:**

- (1) These design performance numbers were obtained using the Quartus II software version 5.0 SP1.
- (2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (4) This application uses registered inputs and outputs.
- (5) This application uses registered multiplier input and output stages within the DSP block.
- (6) This application uses registered multiplier input, pipeline, and output stages within the DSP block.
- (7) This application uses registered multiplier input with output of the multiplier stage feeding the accumulator or subtractor within the DSP block.
- (8) This application uses the same clock source that is globally routed and connected to ports A and B.
- (9) This application uses locally routed clocks or differently sourced clocks for ports A and B.

Parameter	Paths Affected	Available Settings	Minimum Timing (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade	
			Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)
Input delay from pin to internal cells	Pad to I/O dataout to logic array	8	0 0	1,697 1,782	0 0	2,876 3,020	0	3,308	0	3,853
Input delay from pin to input register	Pad to I/O input register	64	0 0	1,956 2,054	0 0	3,270 3,434	0	3,761	0	4,381
Delay from output register to output pin	I/O output register to pad	2	0 0	316 332	0 0	525 525	0	575	0	670
Output enable pin delay	$t_{xz}$ , $t_{zx}$	2	0 0	305 320	0 0	507 507	0	556	0	647

**Notes to Table 5–70:**

- (1) The incremental values for the settings are generally linear. For the exact delay associated with each setting, use the latest version of the Quartus II software.
- (2) The first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.
- (3) The first number applies to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices. The second number applies to -3 speed grade EP2S130 and EP2S180 devices.

## Default Capacitive Loading of Different I/O Standards

See [Table 5–71](#) for default capacitive loading of different I/O standards.

I/O Standard	Capacitive Load	Unit
LVTTTL	0	pF
LVC MOS	0	pF
2.5 V	0	pF
1.8 V	0	pF
1.5 V	0	pF
PCI	10	pF
PCI-X	10	pF
SSTL-2 Class I	0	pF

Table 5–76. Stratix II I/O Output Delay for Row Pins (Part 2 of 3)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit	
			Industrial	Commercial						
2.5 V	4 mA	t <sub>OP</sub>	1128	1183	2091	2194	2403	2523	ps	
		t <sub>DIP</sub>	1086	1140	2036	2137	2340	2450	ps	
	8 mA	t <sub>OP</sub>	1030	1080	1872	1964	2152	2265	ps	
		t <sub>DIP</sub>	988	1037	1817	1907	2089	2192	ps	
	12 mA (1)	t <sub>OP</sub>	1012	1061	1775	1862	2040	2151	ps	
		t <sub>DIP</sub>	970	1018	1720	1805	1977	2078	ps	
1.8 V	2 mA	t <sub>OP</sub>	1196	1253	2954	3100	3396	3542	ps	
		t <sub>DIP</sub>	1154	1210	2899	3043	3333	3469	ps	
	4 mA	t <sub>OP</sub>	1184	1242	2294	2407	2637	2763	ps	
		t <sub>DIP</sub>	1142	1199	2239	2350	2574	2690	ps	
	6 mA	t <sub>OP</sub>	1079	1131	2039	2140	2344	2462	ps	
		t <sub>DIP</sub>	1037	1088	1984	2083	2281	2389	ps	
	8 mA (1)	t <sub>OP</sub>	1049	1100	1942	2038	2232	2348	ps	
		t <sub>DIP</sub>	1007	1057	1887	1981	2169	2275	ps	
	1.5 V	2 mA	t <sub>OP</sub>	1158	1213	2530	2655	2908	3041	ps
			t <sub>DIP</sub>	1116	1170	2475	2598	2845	2968	ps
4 mA		t <sub>OP</sub>	1055	1106	2020	2120	2322	2440	ps	
		t <sub>DIP</sub>	1013	1063	1965	2063	2259	2367	ps	
SSTL-2 Class I	8 mA	t <sub>OP</sub>	1002	1050	1759	1846	2022	2104	ps	
		t <sub>DIP</sub>	960	1007	1704	1789	1959	2031	ps	
SSTL-2 Class II	16 mA (1)	t <sub>OP</sub>	947	992	1581	1659	1817	1897	ps	
		t <sub>DIP</sub>	905	949	1526	1602	1754	1824	ps	
SSTL-18 Class I	4 mA	t <sub>OP</sub>	990	1038	1709	1793	1964	2046	ps	
		t <sub>DIP</sub>	948	995	1654	1736	1901	1973	ps	
	6 mA	t <sub>OP</sub>	994	1042	1648	1729	1894	1975	ps	
		t <sub>DIP</sub>	952	999	1593	1672	1831	1902	ps	
	8 mA	t <sub>OP</sub>	970	1018	1633	1713	1877	1958	ps	
		t <sub>DIP</sub>	928	975	1578	1656	1814	1885	ps	
	10 mA (1)	t <sub>OP</sub>	974	1021	1615	1694	1856	1937	ps	
		t <sub>DIP</sub>	932	978	1560	1637	1793	1864	ps	

**Table 5–86. Maximum DCD for DDIO Output on Row I/O Pins with PLL in the Clock Path (Part 2 of 2)** *Note (1)*

Row DDIO Output I/O Standard	Maximum DCD (PLL Output Clock Feeding DDIO Clock Port)		Unit
	-3 Device	-4 & -5 Device	
LVDS/ HyperTransport technology	180	180	ps

*Note to Table 5–86:*

- (1) The DCD specification is based on a no logic array noise condition.

**Table 5–87. Maximum DCD for DDIO Output on Column I/O with PLL in the Clock Path** *Note (1)*

Column DDIO Output I/O Standard	Maximum DCD (PLL Output Clock Feeding DDIO Clock Port)		Unit
	-3 Device	-4 & -5 Device	
3.3-V LVTTTL	145	160	ps
3.3-V LVCMOS	100	110	ps
2.5V	85	95	ps
1.8V	85	100	ps
1.5-V LVCMOS	140	155	ps
SSTL-2 Class I	65	75	ps
SSTL-2 Class II	60	70	ps
SSTL-18 Class I	50	65	ps
SSTL-18 Class II	70	80	ps
1.8-V HSTL Class I	60	70	ps
1.8-V HSTL Class II	60	70	ps
1.5-V HSTL Class I	55	70	ps
1.5-V HSTL Class II	85	100	ps
1.2-V HSTL	155	-	ps
LVPECL	180	180	ps

*Notes to Table 5–87:*

- (1) The DCD specification is based on a no logic array noise condition.  
 (2) 1.2-V HSTL is only supported in -3 devices.

Table 5–90 shows the high-speed I/O timing specifications for -4 speed grade Stratix II devices.

Symbol	Conditions	-4 Speed Grade			Unit	
		Min	Typ	Max		
$f_{\text{HSCLK}}$ (clock frequency) $f_{\text{HSCLK}} = f_{\text{HSDR}} / W$	W = 2 to 32 (LVDS, HyperTransport technology) (3)	16		520	MHz	
	W = 1 (SERDES bypass, LVDS only)	16		500	MHz	
	W = 1 (SERDES used, LVDS only)	150		717	MHz	
$f_{\text{HSDR}}$ (data rate)	J = 4 to 10 (LVDS, HyperTransport technology)	150		1,040	Mbps	
	J = 2 (LVDS, HyperTransport technology)	(4)		760	Mbps	
	J = 1 (LVDS only)	(4)		500	Mbps	
$f_{\text{HSDRDPA}}$ (DPA data rate)	J = 4 to 10 (LVDS, HyperTransport technology)	150		1,040	Mbps	
TCCS	All differential standards	-		200	ps	
SW	All differential standards	330		-	ps	
Output jitter				190	ps	
Output $t_{\text{RISE}}$	All differential I/O standards			160	ps	
Output $t_{\text{FALL}}$	All differential I/O standards			180	ps	
$t_{\text{DUTY}}$		45	50	55	%	
DPA run length				6,400	UI	
DPA jitter tolerance	Data channel peak-to-peak jitter	0.44			UI	
DPA lock time	<b>Standard</b>	<b>Training Pattern</b>	<b>Transition Density</b>			Number of repetitions
	SPI-4	0000000000 1111111111	10%	256		
	Parallel Rapid I/O	00001111	25%	256		
		10010000	50%	256		
	Miscellaneous	10101010	100%	256		
01010101			256			

**Notes to Table 5–90:**

- (1) When J = 4 to 10, the SERDES block is used.
- (2) When J = 1 or 2, the SERDES block is bypassed.
- (3) The input clock frequency and the W factor must satisfy the following fast PLL VCO specification:  $150 \leq \text{input clock frequency} \times W \leq 1,040$ .
- (4) The minimum specification is dependent on the clock source (fast PLL, enhanced PLL, clock pin, and so on) and the clock routing resource (global, regional, or local) utilized. The I/O differential buffer and input register do not have a minimum toggle rate.